Page 1 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Test Lab Report Summary

Q10157DPA Project: Report Number: **SWIFT** Part Type: Microcircuit System: **BAT** Part Number: MAX4528EUA *Initiated Date:* 05/31/2001 Date Code: Report Date: 9816 09/19/2001

Manufacturer:MAXIMInvestigator:C. Greenwell (562)Generic Number:MAX4528Requester:B. Meinhold (562)

Purchase Spec: Commercial Approval / Date:

Step 1: INCOMING INSPECTION

| Test | Quantity | <u>Passed</u> | <u>Failed</u> | |
|------------------|----------|---------------|---------------|--|
| External Visual | N/A | N/A | N/A | |
| PIND Condition A | N/A | N/A | N/A | |

Step 2: DESTRUCTIVE PHYSICAL ANALYSIS

Destructive Physical Analysis (DPA) was conducted per GSFC document "Plastic Encapsulated Microcircuit (PEM) Guidelines for Screening and Qualification for Space Applications", except that cross-section was done without dye penetrant and glassivation integrity testing was not performed.

No rejectable defects or anomalies were observed during this analysis.

Part No:

MAX4528EUA

Radiographic Examination

Part Type:

Microcircuit

Manufacturer: MAXIM Date Code: 9816 Summary of Analysis: Serial Number 31 32 35 33 34 External Examination 1. Markings - legibility and correctness Α Α Α Α Α 2. Integrity of package seals N/A N/A N/A N/A N/A 3. Condition of external leads and plating _____ Α Α Α Α Α 4. Overall package condition Α Α Α Α A

5. Die bonding material and die alignment Α Α Α Α Α 6. Package seal integrity _____ N/A N/A N/A N/A N/A 7. Presence of foreign material Α Α Α A A

| Theousite interescopy inspection | | | | | |
|---|---|---|---|---|---|
| 9. Condition of material interfaces (delaminations) | A | A | A | A | A |
| 10. Condition of molding material (voids, cracks) | A | A | A | A | A |

Internal Examination (including cross-section)

11. Presence of foreign material ______ A A A A A A

12. Mechanical condition of die A Α Α Α A 13. Wire bonds and lead dress N/P N/P Α Α A 14. Die bonding material Α Α Α Α Α

15. Condition of die surface N/P N/P A A A A A 16. Condition of metallization N/P N/P A A A A A

17. SEM Examination A A A A A

Bond Strength

18. Strength

N/P N/P A A A A

19. Metallization adherence ______ N/P N/P A A A

 Die Bond Strength

 20. Strength
 N/P N/P N/P N/P N/P

 $SN\space{-0.05em}{'}s$ 31 and 32 subjected to cross-sectional examination.

Page 3 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

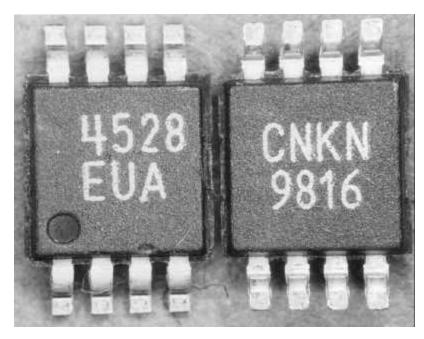


Figure 1. External top and bottom views of the MAX4528EUA devices. 14X

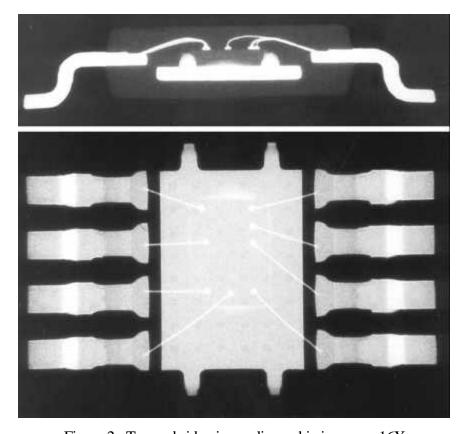


Figure 2. Top and side view radiographic images. 16X

Page 4 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

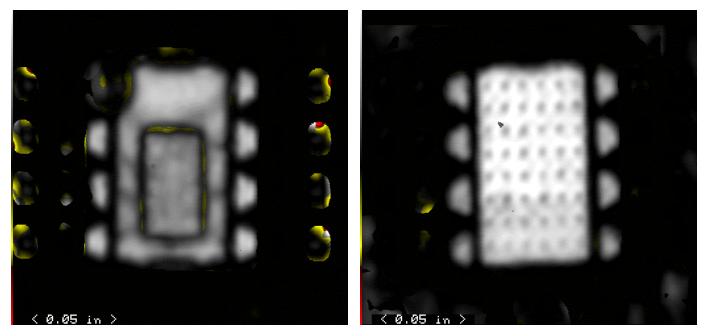


Figure 3. Top (left) and bottom C-SAM images of SN 31.

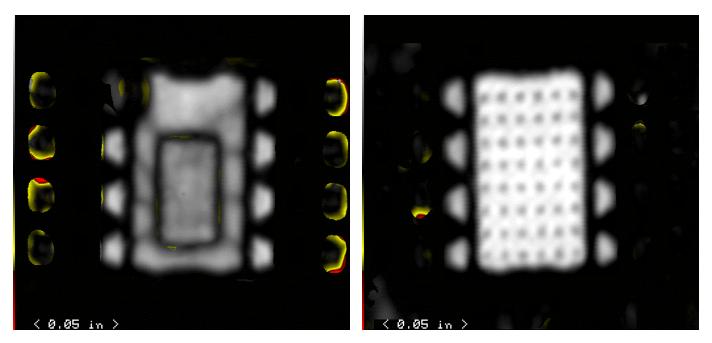


Figure 4. Top (left) and bottom C-SAM images of SN 32.

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

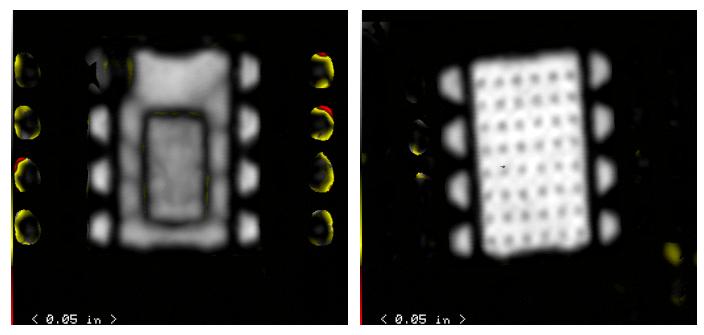


Figure 5. Top (left) and bottom C-SAM images of SN 33.

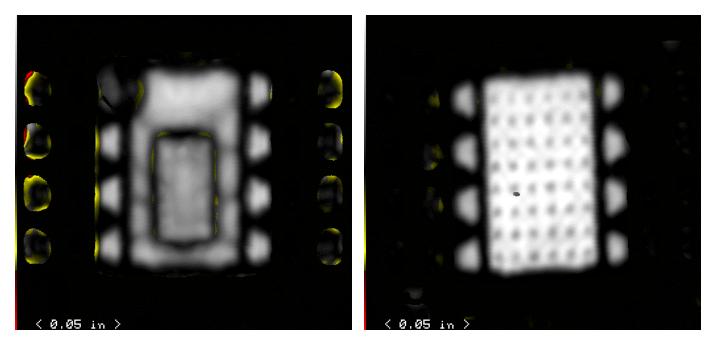


Figure 6. Top (left) and bottom C-SAM images of SN 34.

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

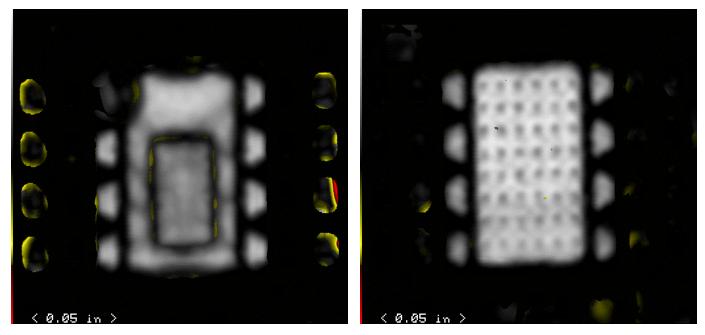


Figure 7. Top (left) and bottom C-SAM images of SN 35. Non-rejectable delaminations are indicated in both views.

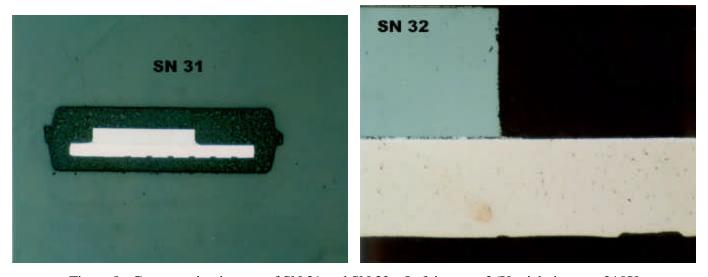


Figure 8. Cross-section images of SN 31 and SN 32. Left image - 26X; right image - 210X

Page 7 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

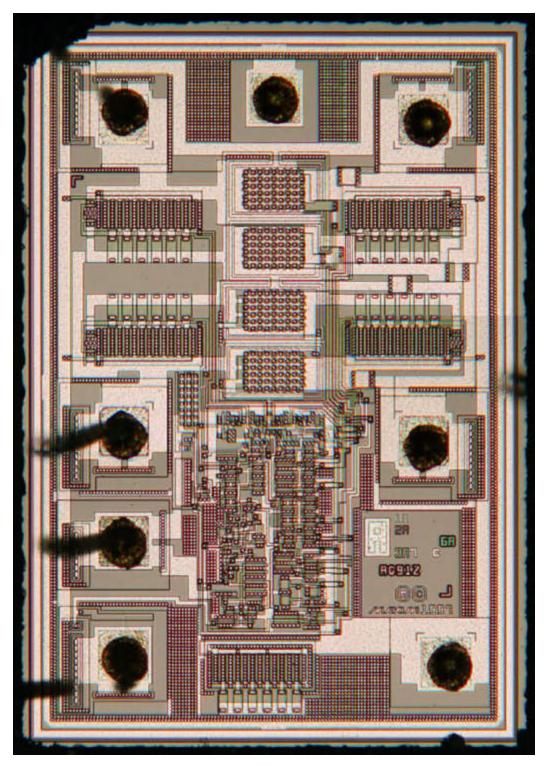


Figure 9. Overall optical image of SN 35 die. The top left corner of the die is obscured by residual molding material.

Page 8 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

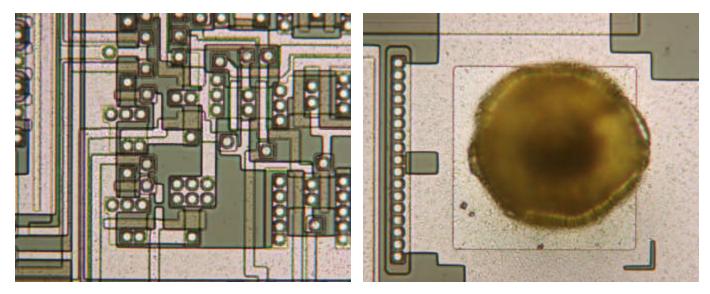


Figure 10. Optical micrograph images show typical features on SN 33 die.

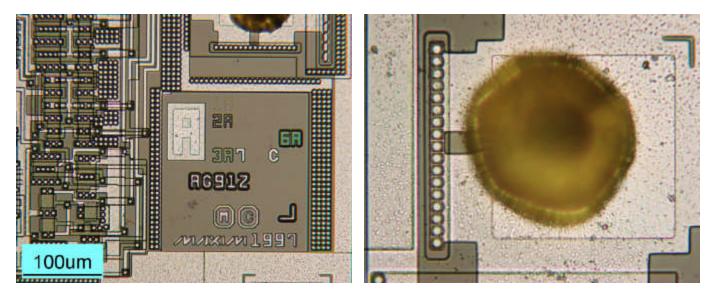


Figure 11. Optical micrograph images of SN 34.

Page 9 of 9 Q10157DPA

GODDARD SPACE FLIGHT CENTER

Part Type: Microcircuit Part No: MAX4528EUA

Manufacturer: MAXIM Date Code: 9816

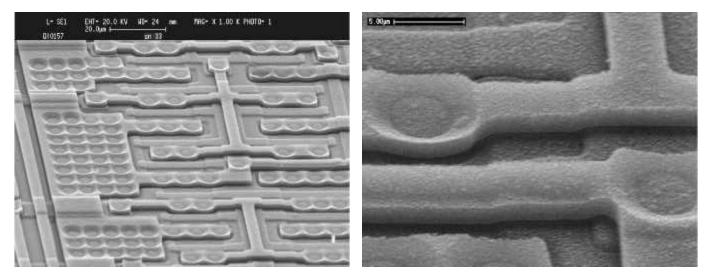


Figure 12. SEM micrographs of SN 33 show general metal features.

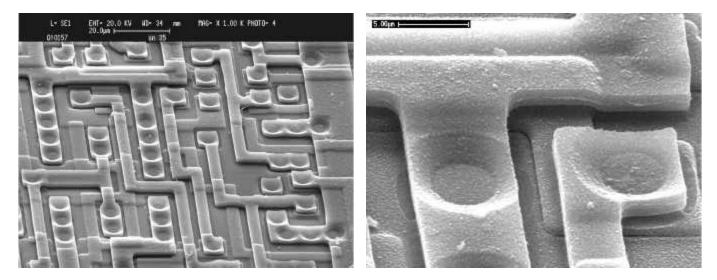


Figure 13. SEM micrographs of SN 35 show general metal features.